



Flom Test Lab
EMI, EMC, RF Testing Experts Since 1963

toll-free: (866) 311-3268
fax: (480) 926-3598
www.flomlabs.com
info@flomlabs.com

Date: February 25, 2009

Applicant: Novatel Wireless Inc.
9645 Scranton Rd, Suite 205
San Diego, CA 92121

Attention of: John Spall, Project Manager
Ph: 858-812-0697, Fax: 858-450-7183
email: jspall@nvtl.com

Equipment: PKRNVWE760D Collocated with QDS-BRCM1030 802.11
FCC ID: PKRNVWE760D
FCC Rules: Radio Frequency Radiation Exposure Limits
47 CFR 1.1310
MPE - Mobiles X Fixed Based Station

Gentlemen:

Enclosed please find your copy of the Supplemental Test Data Report, the whole for Environmental Assessment (MPE) of the referenced equipment as shown.

Please allow from 8-12 weeks to hear from the Commission, who may request additional data or information, and even a sample for pre-grant audit testing.

Should you need any clarification, just fax or phone. Thank you again for this order - it has been a pleasure to be of service.

Sincerely yours,

Hoosamuddin S. Bandukwala, Lab Director



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Date: February 25, 2009

Attention: Federal Communications Commission
Authorization & Evaluation Division

Via: Electronic Filing

Applicant: Novatel Wireless Inc.

Equipment: PKRNVWE760D Collocated with QDS-BRCM1030 802.11

FCC ID: PKRNVWE760D

FCC Rules: Radio Frequency Radiation Exposure Limits
47 CFR 1.1310
MPE - Mobiles X Fixed Based Station

Gentlemen:

On behalf of the Applicant, enclosed please find the Supplemental Test Data Report, the whole for Environmental Assessment (MPE) of the referenced equipment as shown.

We trust the same is in order. Should you need any further information, kindly contact the writer who is authorized to act as agent.

Sincerely yours,

Hoosamuddin S. Bandukwala, Lab Director



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Environmental Assessment

for

Mobiles

for

FCC ID: PKRNVWE760D

Model:PKRNVWE760D Collocated with QDS-BRCM1030

to

Federal Communications Commission

47 CFR 1.1310 (MPE)

Radio Frequency Radiation Exposure Limits

Date Of Report: February 24, 2009

On the Behalf of the Applicant:

Novatel Wireless Inc.

At the Request of:

Novatel Wireless Inc.
9645 Scranton Rd, Suite 205
San Diego, CA 92121

Attention of:

John Spall, Project Manager
Ph: 858-812-0697, Fax: 858-450-7183
email: jspall@nvtl.com

Supervised By:

Hoosamuddin S. Bandukwala, Lab Director

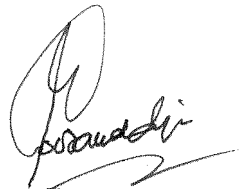
Test Report Revision History

Revision	Date	Revised By	Reason for revision
1.0	February 24, 2009	H Bandukwala	Original Document

Testimonial and Statement of Certification

This is to certify that:

1. **That** the application was prepared either by, or under the direct supervision of, the undersigned.
2. **That** the technical data supplied with the application was taken under my direction and supervision.
3. **That** the data was obtained on representative units, randomly selected.
4. **That**, to the best of my knowledge and belief, the facts set forth in the application and accompanying technical data are true and correct.



Certifying Engineer:

Hoosamuddin S. Bandukwala, Lab Director

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Required information per ISO 17025-2005, paragraph 5.0:

a) **Test Report (Supplemental)**

b) Laboratory: Flom Test Labs
(FCC: 31040/SIT) 3356 N. San Marcos Place, Suite 107
(Canada: IC 2044) Chandler, AZ 85225

c) Report Number:

d) Client: Novatel Wireless Inc.
9645 Scranton Rd, Suite 205
San Diego, CA 92121

e) Identification: PKRNVWE760D
FCC ID: PKRNVWE760D
Description: Laptop model Paltrow 16M (Studio XPS 1640)

f) EUT Condition: Not required unless specified in individual tests.

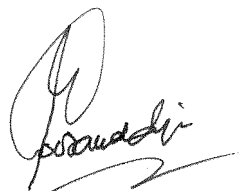
g) Report Date: February 25, 2009

h, j, k): As indicated in individual tests.

i) Sampling method: No sampling procedure used.

l) Uncertainty: In accordance with FTL internal quality manual.

m) Supervised by:



Hoosamuddin S. Bandukwala, Lab Director

n) Results: The results presented in this report relate only to the item tested.

o) Reproduction: This report must not be reproduced, except in full, without written permission from this laboratory.

Identification of the Equipment Under Test (EUT)

Name and Address of Applicant: Novatel Wireless Inc.
9645 Scranton Rd, Suite 205
San Diego, CA 92121

Manufacturer: Novatel Wireless Inc.
9645 Scranton Rd, Suite 205
San Diego, CA 92121

FCC ID: PKRNVWE760D

Model Number: Paltrow 16M (Studio XPS 1640)

Description: Laptop model Paltrow 16M (Studio XPS 1640)

Type of Emission: CDMA collocated with 802.11

Frequency Range, MHz: CDMA 824.7 – 848.31 and 1851.25 – 1908.75
802.11 2412 – 2462

Power Rating, Watts: 0.877
 _____ Switchable _____ Variable X N/A

Modulation: _____ AMPS
 _____ TDMA
 X CDMA
 X OTHER

Antenna: _____ Helical
 _____ Monopole
 _____ Whip
 X Other

Note: For RF Safety test antenna gain taken at the upper range of expected gain (i.e. 0 dBd) and RF Power set to highest nominal power across all channels.

Standard Test Conditions and Engineering Practices

Except as noted herein, the following conditions and procedures were observed during the testing:

In accordance with ANSI C63.4-2003 and unless otherwise indicated in the specific measurement results, the ambient temperature of the actual EUT was maintained within the range of 10° to 40°C (50° to 104 °F) unless the particular equipment requirements specify testing over a different temperature range. Also, unless otherwise indicated, the humidity levels were in the range of 10% to 90% relative humidity.

Prior to testing, the EUT was tuned up in accordance with the manufacturer's alignment procedures. All external gain controls were maintained at the position of maximum and/or optimum gain throughout the testing.

Measurement results, unless otherwise noted, are worst-case measurements.

A2LA

"A2LA has accredited Flom Test Labs, Inc. Chandler, AZ for technical competence in the field of Electrical testing. The accreditation covers the specific tests and types of tests listed on the agreed scope of accreditation. This laboratory meets the requirements of ISO 17025:2005 'General Requirements for the Competence of Testing and Calibration Laboratories' and any additional program requirements in the identified field of testing."

Please refer to www.a2la.org for current scope of accreditation.

Certificate number: 2152.01



Name of Test: Environmental Assessment

Specification: FCC: 47 CFR 1.1310

Measurement Guide: ANSI/IEEE C95.1 1992

Name of Test: R.F. Radiation Exposure

FCC Rules: 1.1307, 1.1310, 1.1311, 2.1091
Description, EUT: See page 2 of Test Report

Limits: Uncontrolled Exposure	0.3-1.234 MHz:	Limit [mW/cm ²] = 100
47 CFR 1.1310	1.34-30 MHz:	Limit [mW/cm ²] = (180/f ²)
Table 1, (B)	30-300 MHz:	Limit [mW/cm ²] = 0.2
	300-1500 MHz	Limit [mW/cm ²] = f/1500
	1500-100,000 MHz:	Limit [mW/cm ²] = 1.0

Test Frequencies, MHz	824 – 848
Power, Conducted, mW	= 877
Antenna Gain	= 3 dBi
Antenna Model	Planer Inverted F Antenna
Distance cm	20

Limit Calculations Limit_[mW/cm²] = 0.549

Test Frequencies, MHz	1851 - 1908
Power, Conducted, mW	= 628
Antenna Gain	= 3 dBi
Antenna Model	Planer Inverted F Antenna
Distance cm	20

Limit Calculations Limit_[mW/cm²] = 1.0

PKRNVWE760D CDMA

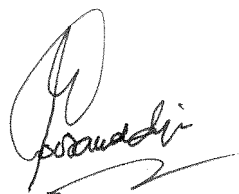
CDMA Frequency MHz	TX Power (m)W	Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
824 - 848	877	0.348	0.549	Pass
1851 - 1908	628	0.249	1.0	Pass

QDS-BRCM1030 802.11

802.11 a,b,g Frequency MHz	TX Power (mW)	Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
2412 – 2462	202	0.080	1.0	Pass

PKRNVWE760D CDMA Collocated with QDS-BRCM1030 802.11

CDMA Frequency MHz	802.11.a,b,g Frequency MHz	CDMA Power Density (mW/cm ²)	802.11.a,b,g Power Density (mW/cm ²)	Total Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
824 – 848	2412 – 2462	0.348	0.080	0.428	0.549	Pass
1851 - 1908	2412 – 2462	0.249	0.080	0.329	1.0	Pass



Supervised By:

Hoosamuddin S. Bandukwala, Lab Director